EXPRESS MAIL LABEL NO. EV381146341US

Abstract of the Disclosure

PROCESS FOR FABRICATING A SEMICONDUCTOR DEVICE COMPRISING A GATE DIELECTRIC MADE OF HIGH DIELECTRIC PERMITTIVITY MATERIAL

A process and a device for fabricating a semiconductor device having a gate dielectric made of high-k material, includes a step of depositing, directly on the gate dielectric, a first layer of $Si_{1-x}Ge_x$, where $0.5 < x \le 1$, at a temperature substantially below the temperature at which a poly-Si is deposited by thermal chemical vapor deposition (CVD).